

<b>Notice of References Cited</b>	Application/Control No. 09/594,995	Applicant(s)/Patent Under Reexamination KATAYAMA ET AL.	
	Examiner Devona E. Faulk	Art Unit 2644	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,272,757	12-1993	Scofield et al.	381/381
	B	US-			
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	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	N	EP 563929 A2	10-1993	European Patent	SEKINE et al.	
	O	JP 07015395 A	01-1995	Japan	TAKEDA et al.	
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
*	U	Applicant's admitted prior art (Figures 11 and 12), page 1, line 15-page 4, line 3
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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